

PCN #189 Notification Date: June 19, 2020

145 Adams Avenue, Hauppauge, NY 11788 USA Tel: (631) 435-1110 • Fax: (631) 435-1824 www.centralsemi.com mailto:processchange@centralsemi.com https://www.centralsemi.com/process-change-notices

Product / Process Change Notice

Parts Affected:

Chip process CP371, N-channel MOSFETs, wafers and bare die.

Extent of Change:

The CP371 wafer process has been discontinued and is being replaced with the CP405 wafer process. See Figures 1 and 2 for details.

Reason for Change:

The CP371 wafer process has been replaced in order to enhance manufacturing process controls and device performance. This change will help ensure an undisrupted supply of product.

Effect of Change:

The CP405 wafer process meets all electrical specifications of the individual devices listed on the following page.

Qualification:

P/N: CP405 Chip Process Package: TO-220 Conditions No. Test (Reference standards are in Qty Pass/Fail **Test Results** bold) **Device Life Tests** 1 T=150°C, t = 1000 hours 100% V_GS **High Temperature** А 77 77/77 Pass Gate Bias (HTGB) **Negative Bias** JESD22-A108 T=150°C, t = 1000 hours **High Temperature** 100% V_GS В 77 Pass 77/77 Gate Bias (HTGB) **Positive Bias** JESD22-A108 **High Temperature** T=150°C, t = 1000 hours С 77 **Reverse Bias** 100% V_DS 77/77 Pass (HTRB) JESD22-A108



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Effective Date of Change:

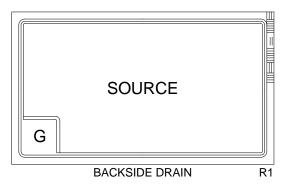
Existing inventory of chip process CP371 will be shipped until depleted.

Sample Availability:

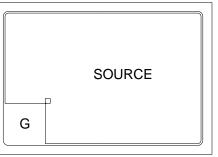
Please contact your salesperson or manufacturer's representative for samples.

Figure 1: CP371 Chip Geometry (Discontinued)

Figure 2: CP405 Chip Geometry



| Wafer Diameter: | 8 inch |
|---|--|
| Die Size: | 55 x 32 mils |
| Die Thickness: | 7.5 mils |
| Bond Pad Size (Gate): | 7.3 x 7.3 mils |
| Bond Pad Size (Source): | 50 x 25 mils |
| Topside Metal: | Al (40,000Å) |
| . , , , , , , , , , , , , , , , , , , , | Al (40,000Å) Ti/Ni/Ag (1,000Å/3,000Å/10,000Å) |



BACKSIDE DRAIN

| Wafer Diameter: | 8 inch |
|-------------------------|----------------------------------|
| Die Size: | 45.7 X 31.9 mils |
| Die Thickness: | 5.5 mils |
| Bond Pad Size (Gate): | 8.1 x 8.1 mils |
| Bond Pad Size (Source): | |
| Topside Metal: | Al-Cu (40,000Å) |
| Backside Metal: | Ti/Ni/Ag (1,000Å/3,000Å/10,000Å) |

Part Numbers Affected:

| CP371-WN | CXDM4060N |
|-----------|-----------|
| CP3/1-WIN | |



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As per JEDEC standard JESD46, Customer Notification of Product/Process Changes by Solid-State Suppliers, a lack of acknowledgement of a PCN within thirty (30) days constitutes acceptance of the change.

The undersigned acknowledges and accepts Central Semiconductor's Product/Process Change Notification (PCN).

| Company Name: | |
|---------------|--|
| Address: | |
| | |
| Printed Name: | |
| Title: | |
| Signature: | |
| Date: | |